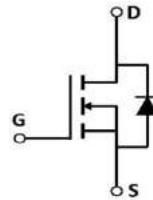


**100V N-SGT Enhancement Mode MOSFET**
**General Description**

12N10D use advanced SGT MOSFET technology to provide low RDS(ON), low gate charge, fast switching and excellent avalanche characteristics.

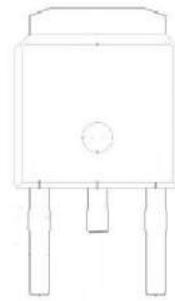
This device is specially designed to get better ruggedness and suitable to use in


**Features**

Low RDS(on) & FOM

Extremely low switching loss

Excellent stability and uniformity or Invertors


**Applications**

Consumer electronic power supply

Motor control

Synchronous-rectification

Isolated DC

Synchronous-rectification applications


**Absolute Maximum Ratings** at  $T_j=25^\circ\text{C}$  unless otherwise noted

Parameter	Symbol	Value	Unit
Drain source voltage	VDS	100	V
Gate source voltage	VGS	$\pm 20$	V
Continuous drain current <sup>1)</sup> , $T_c=25\ ^\circ\text{C}$	$I_D$	12	A
Pulsed drain current <sup>2)</sup> , $T_c=25\ ^\circ\text{C}$	$I_D$ , pulse	24	A
Power dissipation <sup>3)</sup> , $T_c=25\ ^\circ\text{C}$	$P_D$	17	W
Single pulsed avalanche energy <sup>5)</sup>	EAS	1.2	mJ
Operation and storage temperature	$T_{stg}, T_j$	-55 to 150	$^\circ\text{C}$
Thermal resistance, junction-case	$R_{\theta JC}$	7.4	$^\circ\text{C}/\text{W}$
Thermal resistance, junction-ambient <sup>4)</sup>	$R_{\theta JA}$	62	$^\circ\text{C}/\text{W}$

**100V N-SGT Enhancement Mode MOSFET**
**Electrical Characteristics** at  $T_j=25\text{ }^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
$\text{BV}_{\text{DSS}}$	Drain-source breakdown voltage	$V_{\text{GS}}=0\text{ V}, I_{\text{D}}=250\text{ }\mu\text{A}$	100	111		V
$V_{\text{GS(th)}}$	Gate threshold voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\text{ }\mu\text{A}$	1.2	2.0	2.5	V
$R_{\text{DS(ON)}}$	Drain-source on-state resistance	$V_{\text{GS}}=10\text{ V}, I_{\text{D}}=5\text{ A}$		105	125	$\text{m}\Omega$
$R_{\text{DS(ON)}}$	Drain-source on-state resistance	$V_{\text{GS}}=4.5\text{ V}, I_{\text{D}}=3\text{ A}$		115	145	$\text{m}\Omega$
$I_{\text{GSS}}$	Gate-source leakage current	$V_{\text{GS}}=20\text{ V}$			100	nA
		$V_{\text{GS}}=-20\text{ V}$			-100	
$I_{\text{DSs}}$	Drain-source leakage current	$V_{\text{DS}}=100\text{ V}, V_{\text{GS}}=0\text{ V}$			1	uA
$C_{\text{iss}}$	Input capacitance	$V_{\text{GS}}=0\text{ V},$ $V_{\text{DS}}=50\text{ V},$ $f=100\text{ kHz}$		206.1		pF
$C_{\text{oss}}$	Output capacitance			28.9		pF
$C_{\text{rss}}$	Reverse transfer capacitance			1.4		pF
$t_{\text{d(on)}}$	Turn-on delay time	$V_{\text{GS}}=10\text{ V},$ $V_{\text{DS}}=50\text{ V},$ $R_{\text{G}}=2\text{ }\Omega,$ $I_{\text{D}}=5\text{ A}$		14.7		ns
$t_r$	Rise time			3.5		ns
$t_{\text{d(off)}}$	Turn-off delay time			20.9		ns
$t_f$	Fall time			2.7		ns
$Q_g$	Total gate charge	$I_{\text{D}}=5\text{ A},$ $V_{\text{DS}}=50\text{ V},$ $V_{\text{GS}}=10\text{ V}$		4.3		nC
$Q_{\text{gs}}$	Gate-source charge			1.5		nC
$Q_{\text{gd}}$	Gate-drain charge			1.1		nC
$V_{\text{plateau}}$	Gate plateau voltage			5.0		V
$I_s$	Diode forward current	$V_{\text{GS}} < V_{\text{th}}$			7	A
$I_{\text{sp}}$	Pulsed source current				21	
$V_{\text{SD}}$	Diode forward voltage	$I_{\text{S}}=7\text{ A}, V_{\text{GS}}=0\text{ V}$			1.0	V
$t_{\text{rr}}$	Reverse recovery time	$I_{\text{S}}=5\text{ A}, \text{di/dt}=100\text{ A}/\mu\text{s}$		32.1		ns
$Q_{\text{rr}}$	Reverse recovery charge			39.4		nC
$I_{\text{rrm}}$	Peak reverse recovery current			2.1		A

**Note**

- 1) Calculated continuous current based on maximum allowable junction temperature.
- 2) Repetitive rating; pulse width limited by max. junction temperature.
- 3)  $P_d$  is based on max. junction temperature, using junction-case thermal resistance.
- 4) The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_a=25\text{ }^\circ\text{C}$ .
- 5)  $V_{DD}=50\text{ V}, R_G=50\text{ }\Omega, L=0.3\text{ mH, starting }T_j=25\text{ }^\circ\text{C}$ .

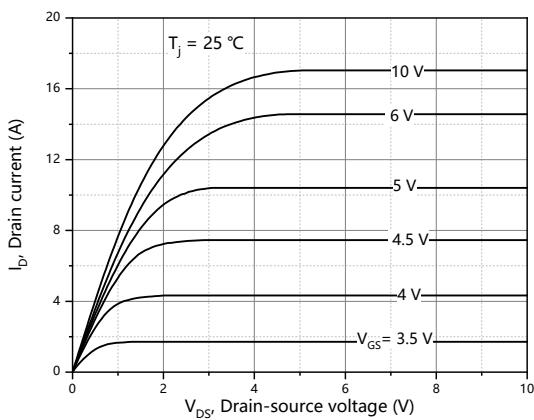
**100V N-SGT Enhancement Mode MOSFET**
**Electrical Characteristics Diagrams**


Figure 1, Typ. output characteristics

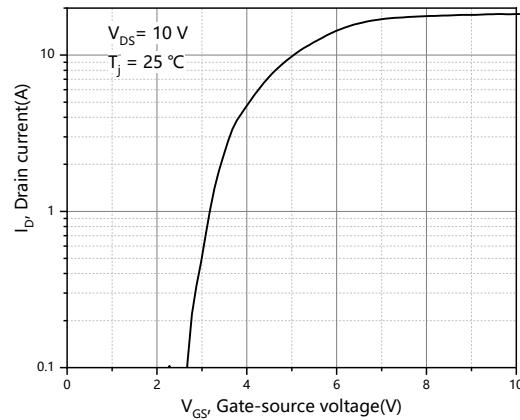


Figure 2, Typ. transfer characteristics

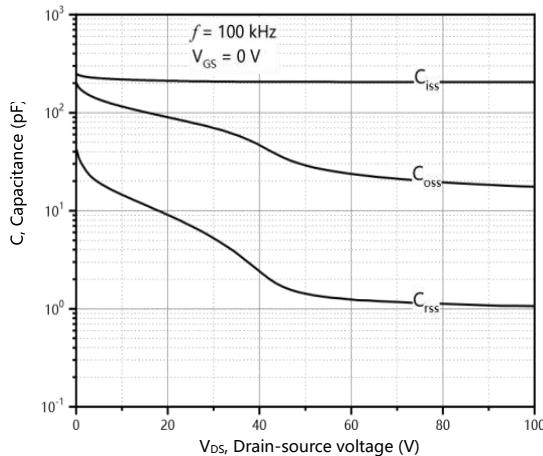


Figure 3, Typ. capacitances

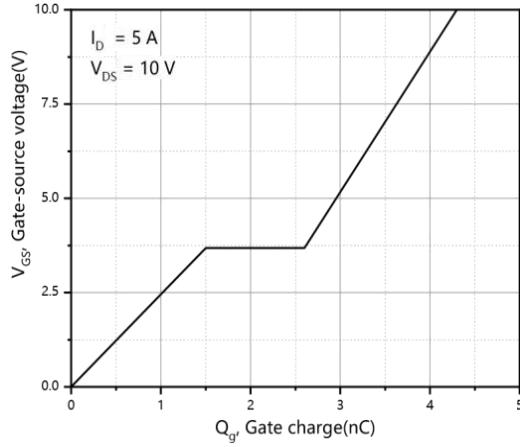


Figure 4, Typ. gate charge

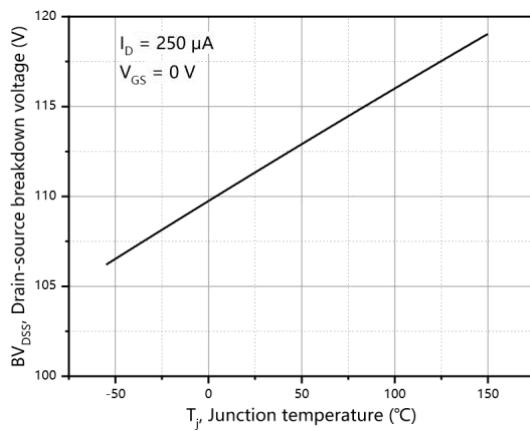


Figure 5, Drain-source breakdown voltage

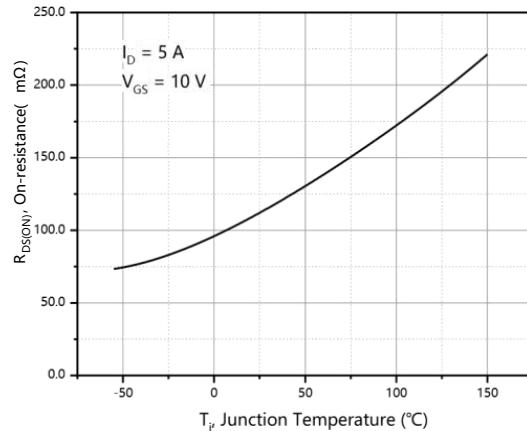


Figure 6, Drain-source on-state resistance

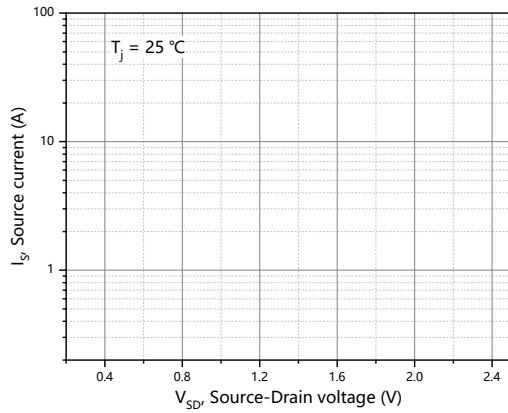
**100V N-SGT Enhancement Mode MOSFET**


Figure 7, Forward characteristic of body diode

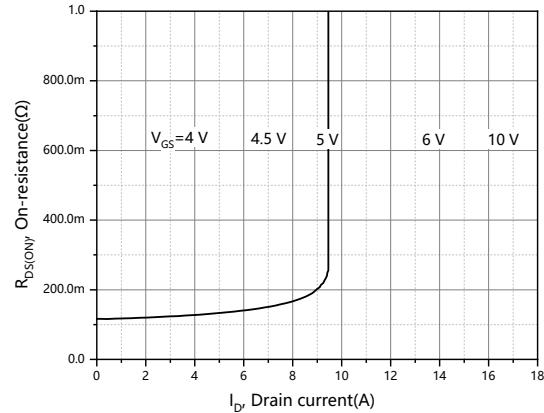


Figure 8, Drain-source on-state resistance

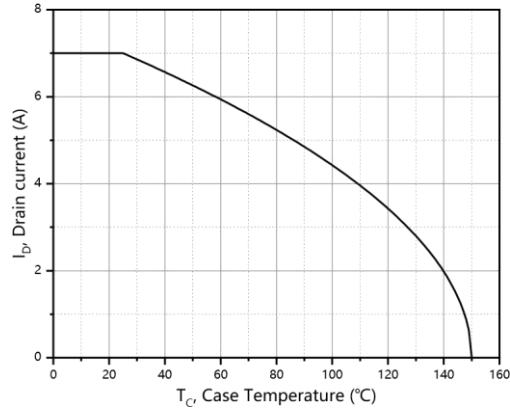


Figure 9, Drain current

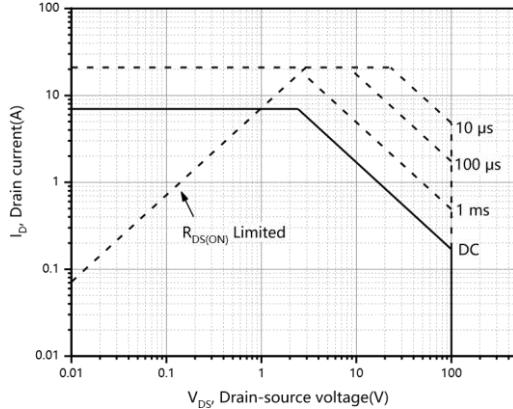


Figure 10, Safe operation area  $T_c=25\text{ }^\circ\text{C}$

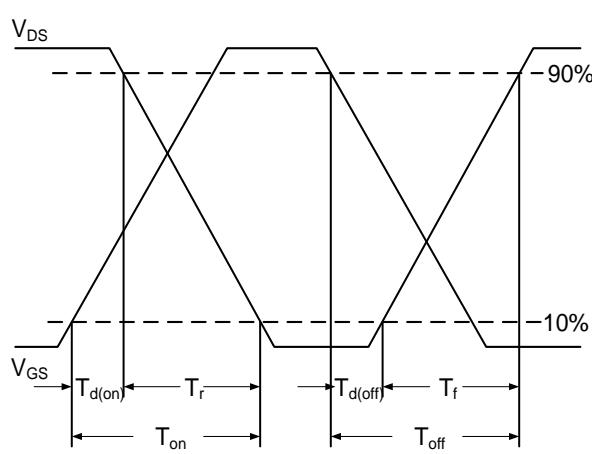


Fig.11 Switching Time Waveform

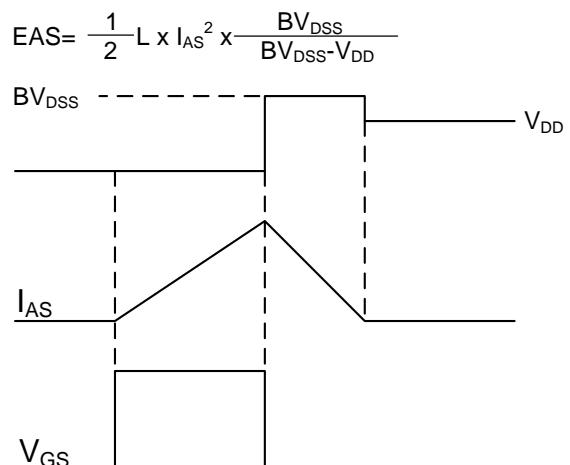
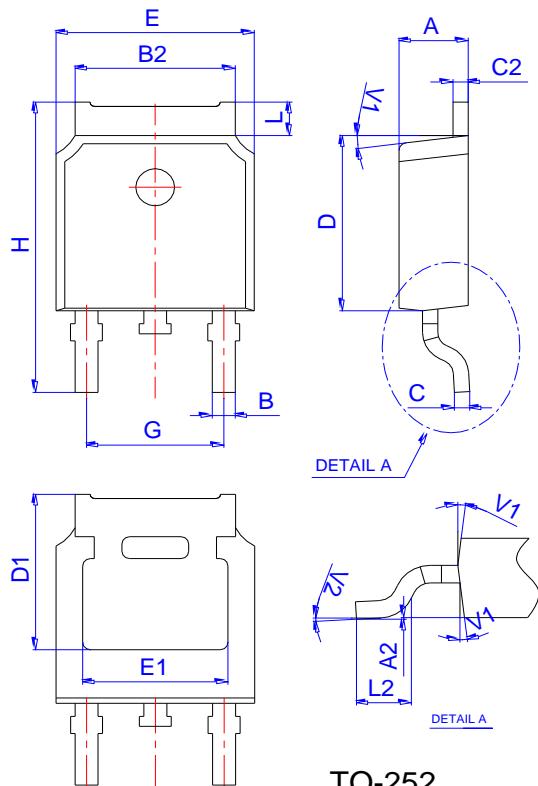
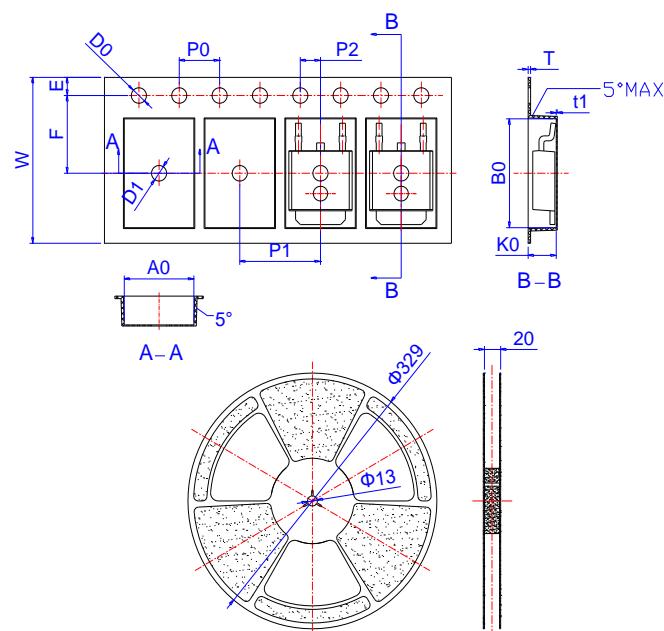


Fig.12 Unclamped Inductive Switching Waveform

**100V N-SGT Enhancement Mode MOSFET**
**Package Mechanical Data-TO-252-3L**

**TO-252**

Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
B	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
C	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
H	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

**Reel Specification-TO-252**


Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
B0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
T	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583